



National Institute of Standards & Technology

Certificate

Standard Reference Material[®] 4416L

Gallium-67 Radioactivity Standard

Lot Number 35

Ampoule 1

This Standard Reference Material (SRM) consists of a solution of a standardized and certified quantity of radioactive gallium-67 in a suitably stable and homogeneous matrix. It is intended primarily for the calibration of instruments that are used to measure radioactivity and for the monitoring of radiochemical procedures. A unit of SRM 4416L consists of approximately 5 mL of a solution, whose composition is specified in Table 1 and 2, contained in a flame-sealed borosilicate-glass ampoule [1].

The certified **gallium-67** massic activity value, at a **Reference Time of 0800 EST, 14 May 2014**, is:
 $(20.19 \pm 0.19) \text{ MBq}\cdot\text{g}^{-1}$

A NIST certified value, as used within the context of this certificate, is a value for which NIST has the highest confidence in its uncertainty assessment. It is a “measurement result” [2] obtained directly or indirectly from a “primary reference measurement procedure” [3]. The certified value is traceable to the derived SI unit, becquerel (Bq).

Additional physical, chemical, and radiological properties for this SRM, as well as details on the standardization method, are given in Table 1 and 2. Uncertainties for the certified quantities are expanded ($k = 2$). The uncertainties are calculated according to the ISO and NIST Guide [4,5]. Table 3 contains a specification of the components that comprise the uncertainty analyses.

Expiration of Certification: The certification of **SRM 4416L** is valid, within the measurement uncertainty specified, within its half-life-dependent useful lifetime, provided the SRM is handled in accordance with instructions given in this certificate (see “Instructions for Handling and Storage”). The certification is nullified if the SRM is damaged, contaminated, or otherwise modified.

Maintenance of Certification: NIST will monitor this SRM over the period of its certification. If substantive technical changes occur that affect the certification, NIST will notify the purchaser.

Radiological and Chemical Hazard: Consult the Safety Data Sheet (SDS), enclosed with the SRM shipment, for radiological and chemical hazard information.

This SRM was prepared in the Physical Measurement Laboratory, Radiation Physics Division, Radioactivity Group, M.P. Unterwiesing, Group Leader. The overall production, technical direction and physical measurement leading to certification were provided by R.K. Young and D.B. Golas, Guest Researchers from NRMAT, Incorporated.

Support aspects involved in the issuance of this SRM were coordinated through the NIST Measurement Services Division.

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Table 1. Certified Massic Activity of SRM 4416L, Lot 35, Ampoule 1

Radionuclide	Gallium-67
Reference time	0800 EST, 14 May 2014
Massic activity of the solution	20.19 MBq•g⁻¹
Relative expanded uncertainty ($k = 2$)	0.96 %^(a)

^(a)The uncertainties on certified values are expanded uncertainties, $U = ku_c$. The quantity u_c is the combined standard uncertainty calculated according to the ISO and NIST Guides [4,5]. The combined standard uncertainty is multiplied by a coverage factor of $k = 2$ and was chosen to obtain an approximate 95 % level of confidence.

Table 2. Uncertified Information of SRM 4416L, Lot 35, Ampoule 1

Source description	Liquid in a flame-sealed 5-mL NIST borosilicate ampoule [1]
Solution composition	2 mol•L ⁻¹ HCl with 74 µg Ga ⁺³ per gram of solution (as GaCl ₃)
Solution density	(1.035 ± 0.002) g•mL ⁻¹ at 20.0 °C ^(a)
Solution mass	(5.1676 ± 0.0003) g ^(a)
Photon-emitting impurities	None detected ^(b)
Half life used	⁶⁷ Ga: (3.2613 ± 0.0005) d [©]
Calibration method (and instruments)	Measurements of ionization current ratios relative to radium-226 reference sources using NIST pressurized "4π"γ ionization chamber "A" calibrated with a gallium-67 solution whose activity was determined by 4π(e+X)-γ-anti-coincidence efficiency-extrapolation technique, using liquid scintillation for the e+X detection and NaI for the γ-ray detection, with confirmatory measurements by 4πγ(NaI) integral counting

^(a)The stated uncertainty is two times the standard uncertainty.

^(b)The estimated lower limits of detection for photon-emitting impurities, expressed as massic photon emission rates, as of 16 May 2014 were:

$3 \times 10^3 \text{ s}^{-1}\cdot\text{g}^{-1}$ for energies between 30 keV and 70 keV,
 $7 \times 10^3 \text{ s}^{-1}\cdot\text{g}^{-1}$ for energies between 75 keV and 110 keV,
 $3 \times 10^3 \text{ s}^{-1}\cdot\text{g}^{-1}$ for energies between 115 keV and 165 keV,
 $6 \times 10^3 \text{ s}^{-1}\cdot\text{g}^{-1}$ for energies between 170 keV and 200 keV,
 $3 \times 10^3 \text{ s}^{-1}\cdot\text{g}^{-1}$ for energies between 205 keV and 280 keV,
 $6 \times 10^3 \text{ s}^{-1}\cdot\text{g}^{-1}$ for energies between 285 keV and 320 keV,
 $1 \times 10^3 \text{ s}^{-1}\cdot\text{g}^{-1}$ for energies between 330 keV and 370 keV,
 $4 \times 10^3 \text{ s}^{-1}\cdot\text{g}^{-1}$ for energies between 380 keV and 410 keV,
 $8 \times 10^2 \text{ s}^{-1}\cdot\text{g}^{-1}$ for energies between 420 keV and 860 keV,
 $1 \times 10^3 \text{ s}^{-1}\cdot\text{g}^{-1}$ for energies between 870 keV and 910 keV,
 $7 \times 10^2 \text{ s}^{-1}\cdot\text{g}^{-1}$ for energies between 920 keV and 1430 keV,
 $1 \times 10^3 \text{ s}^{-1}\cdot\text{g}^{-1}$ for energies between 1440 keV and 1480 keV, and
 $6 \times 10^2 \text{ s}^{-1}\cdot\text{g}^{-1}$ for energies between 1490 keV and 2000 keV,

provided that any impurity photons are separated by four keV or more from photons emitted in the decay of gallium-67.

^(c)The stated uncertainty is the standard uncertainty. See reference 6.

Table 3. Uncertainty Evaluation for the Massic Activity of SRM 4416L, Lot 35

	Uncertainty component	Assessment Type ^(a)	Relative standard uncertainty contribution on massic activity of gallium-67 (%)
1	Ionization-chamber measurement precision for the low-level solution (SRM 4416L, Lot 35); standard deviation of the mean for two sets of measurements on ten ampoules	A	0.01
2	"4 π " γ ionization-chamber calibration factor	B	0.47
3	Effect of carrier concentration and density changes on ionization-chamber response	B	0.04
4	Decay correction for radium-226 reference source to correct the calibration factor (for half-life uncertainty of 0.44 %)	B	0.0008
5	Radium reference source positioning	B	0.05
6	Ionization-chamber charge collection	B	0.05
7	Gravimetric mass measurements	B	0.05
8	Decay correction for gallium-67 (for half-life uncertainty of 0.015 %)	B	0.00002
9	Detection limits for photon-emitting impurities	B	0.02
Relative combined standard uncertainty			0.48
Relative expanded uncertainty ($k = 2$)			0.96

^(a)Letter A denotes evaluation by statistical methods; B denotes evaluation by other methods.

INSTRUCTIONS FOR HANDLING AND STORAGE

Handling: If the ampoule is transported, it should be packed, marked, labeled, and shipped in accordance with the applicable national, international, and carrier regulations. The solution in the ampoule is a dangerous good (hazardous material) because of both the radioactivity and the strong acid. The ampoule should be opened only by persons qualified to handle both radioactive material and alkaline and/or acidic solutions. Appropriate shielding and/or distance should be used to minimize personnel exposure. Refer to the SDS for further information.

Storage: SRM 4416L should be stored and used at a temperature between 5 °C and 65 °C. The ampoule (or any subsequent container) should always be clearly marked as containing radioactive material.

REFERENCES

- [1] NIST Physical Measurement Laboratory; *Storage and Handling of Radioactive Standard Reference Materials, Ampoule Specifications and Opening Procedure*; available at <http://www.nist.gov/pml/div682/grp04/srm.cfm>.
- [2] JCGM 200:2012; *International Vocabulary of Metrology - Basic and General Concepts and Associated Terms (VIM)* (2008 version with Minor Corrections), 3rd edition; Joint Committee for Guides in Metrology: BIPM, Sèvres Cedex, France; p. 19 (2012); available at http://www.bipm.org/utls/common/documents/jcgm/JCGM_200_2012.pdf.
- [3] JCGM 200:2012; *International Vocabulary of Metrology - Basic and General Concepts and Associated Terms (VIM)* (2008 version with Minor Corrections), 3rd edition; Joint Committee for Guides in Metrology: BIPM, Sèvres Cedex, France; p. 18 (2012); available at http://www.bipm.org/utls/common/documents/jcgm/JCGM_200_2012.pdf.
- [4] JCGM 100:2008; *Guide to the Expression of Uncertainty in Measurement*; (ISO GUM 1995 with Minor Corrections), Joint Committee for Guides in Metrology: BIPM, Sèvres Cedex, France (2008); available at http://www.bipm.org/utls/common/documents/jcgm/JCGM_100_2008_E.pdf.
- [5] Taylor, B.N.; Kuyatt, C.E.; *Guidelines for Evaluating and Expressing the Uncertainty of NIST Measurement Results*; NIST Technical Note 1297, U.S. Government Printing Office: Washington, DC (1994); available at <http://physics.nist.gov/Pubs/>.
- [6] Laboratoire National Henri Becquerel; *Table of Radionuclides, Recommended Data* (updated 22 November 2012); available at http://www.nucleide.org/DDEP_WG/DDEPdata.htm (accessed May 2014).

Users of this SRM should ensure that the Certificate in their possession is current. This can be accomplished by contacting the SRM Program: telephone (301) 975-2200; fax (301) 948-3730; e-mail srminfo@nist.gov; or via the internet at <http://www.nist.gov/srm>.